Application/Control No. O9/783,254 Examiner Hieu Phan Applicant(s)/Patent Under Reexamination SIRHAN ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,283,257	02-1994	Gregory et al.	514/458
	В	US-			
	ပ	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	н	US-			
	-	US-			
	J	US-			
	κ	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0		·			
	Ρ					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	٧	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.